

## ASIGURAREA CALITĂȚII – QUALITY ASSURANCE

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# How to apply Risk-based Thinking to ISO 9001:2015

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## **Abstract**

Risk-based thinking (RBT) looks to be here to stay in ISO 9001:2015 and other ISO standards. It is increasingly important for certification to be able to demonstrate evidence that you have applied RBT. To do this, you might look to ISO 31000 – Risk management and its list of risk assessment techniques, but this is not as easy as it sounds. We therefore propose a ‘best practices’ guideline in the form of a six-step methodology that is intended to be both easy-to-follow and appropriate for the resources available to a typical small-to-medium enterprise (SME).

**Keywords:** ISO 9001:2015, ISO 31000, Risk, Risk-based thinking, Risk assessment methodology

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# Cultural Service Quality Management in the Context of the Global Economic Crisis

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## **Abstract**

It suffices to browse the websites of only a few of the most noteworthy Romanian cultural organizations – including the website of the Ministry of Culture – to conclude that quality policies are missing. In fact, these are not the only policies that are missing, but this topic should be discussed in another paper. The objective of this paper is to analyze the progresses and the opportunities, as well as the problems and the challenges that the Romanian society and economy are facing as far as culture is concerned at the beginning of the new millennium, in the particular context of the global economic crisis: specifically, we will focus on the role of cultural organization managers in implementing quality management as the main factor in assuring the competitiveness needed to overcome the crisis. Cultural organization managers generally admit that a change is needed in order to cope with competitive pressure, but few understand how this change should be implemented. To avoid the issues associated with „change programs“, the management of cultural organizations must focus on the structure of processes, recognizing the roles and responsibilities of their employees in the processes in which they are involved.

**Keywords:** quality management, culture, cultural organizations, consumer, cultural services, competitiveness, global economic crisis

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# CORAS - O platformă de analiză a riscului pentru sistemele critice

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## **Abstract**

This paper analyses the CORAS platform, which is an open-source and data-portable tool for risk evaluation. It has been developed by a consortium of partners from four European countries. CORAS is a model-driven method for defensive risk analysis featuring a tool-supported modelling language specially designed to model risks. The CORAS tool is well-suited for creating risk models on-the-fly during brainstorming session. In this paper, the authors make a critical presentation of the platform CORAS, mentioning its advantages and limits. A brief overview of modeling language, working method and computer tool with examples of working diagrams are presented.

**Keywords:** CORAS, risk, risk management, risk analysis, open-source, platform, modeling language, computer tool.

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# Micro and Nanodevices, Manufacturability, and Reliability

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## Abstract

The paper takes a fresh look at lessons learned and where things stand today, along with prospects for a bright future. The MEMS industry is currently at a much more vulnerable position than it appears, regardless of how wonderful its future may look like. A full understanding of the physics and statistics of the defect generation is required to investigate the ultimate reliability limitations for nanodevices. Biggest challenge: cost effective, high volume production.

**Keywords:** component, carbon nanotubes (CNT), fabrication, manufacturability, failure analysis, EHS, MEMS, MEOMS, nanodevices, NEMS, packaging, reliability.

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